				~			heet 1 of			
FORM PTO-14	49 (SU	BSTITUTE)	Attorney Docket No.: Divisional of Applic. No. PEK-In1163 D 10/200,934							
		OF COMMERCE		Applicant Wilhelm Asam et al.						
PATENT AND	IKAD	EMARK OFFICE								
INFO	RMA	TION DISCLOSURE								
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	(37)	CFR 1.98(b))								
							 			
EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE			
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Svn	В	5,751,015	05/98	Corbett et al.	257	48				
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Sym	Н	5,280,327	01/94	Buks	396	389				
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		FOREI	GN PATE	NT DOCUMENT						
		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL YES NO			
	J	DOCUMENT NO.	DATE	COUNTRY	CLASS	CLASS	LESTING			
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				ot citation is in conford. Include copy of this						

FORM PTO-14	•	•	Attorney Docket No.: Divisional of Applic. No. PEK-In1163 D 10/200,934							
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